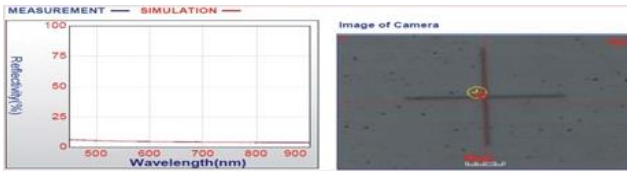


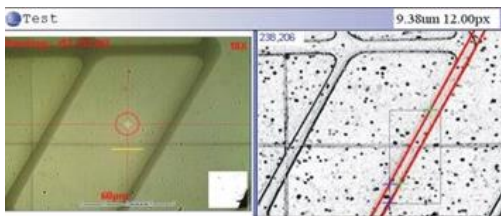
# 多功能拉曼膜厚測量儀



## <反射率>



## <線寬>



## <膜厚>

Index Name	Material	Thickness ( $\mu\text{m}$ )
Ambient	VOID	
Layer - 1	PR 20 $\mu\text{m}$	19.24581 $\pm$ 0.083543
Substrate	SICR	

- 顯微拉曼光譜測量
- 全光譜反射率測量儀
- 高倍光學顯微鏡
- 自動線寬量測
- 量測時間1-3秒
- 精確度高
- 量測膜厚(N. K)值
- 反射率(R%)

Labguide Co., Ltd. (Taiwan)

E-mail : terry@seed.net.tw

Tel. : +886-2-29406162

Add. : 3F., No.37, Ln. 232, Huaxin St., Zhonghe Dist.,  
New Taipei City 235, Taiwan (R.O.C.)

<http://www.labguide.com.tw>

Labguide Co., Ltd. (Shenzhen)

E-mail : admin@labguide.com.cn

Tel. : +86-075527750787

Add. : C603, Baohe Building, No.98 of Baonong North  
Alley, Bao'an District, Shenzhen, China

<http://www.labguide.com.cn>